Dock t No. ent's Address In Applicati n (37 CFR 1.8(a)) TWI-10820 In R Appli losencwaig et al. COPY OF PAPERS **ORIGINALLY FILED** Serial No. Filing Date Examiner **Group Art Unit** 09/629,407 August 1, 2000 Unknown 2876 Invention: MEASUREMENT OF THIN FILMS AND BARRIER LAYERS ON PATTERNED WAFERS WITH X-RAY REFLECTOMETRY TO THE ASSISTANT COMMISSIONER FOR PATENTS PI ase send all correspondence for this application to: STALLMAN & POLLOCK LLP Attn: Michael A. Stallman 121 Spear Street, Suite 290 San Francisco, CA 94105 TECHNOLOGY CENTER 2800 PI ase direct all telephone calls to: Michael A. Stallman Telephone: (415) 512-1312 Facsimile: (415) 512-1362 Dated: April 18, 2002 Signature of Attorney or Agent of Record Michael A. Stallman (Reg. No. 29,444) certify that this document is being deposited on April 18, 2002

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I certify that this document is being deposited on April 18, 2002 with the U.S. Postal Service as first class mail under 37 C.F.R. 1.8 and is addressed to the Assistant Commissioner for Patents, Washington, D.C. 20231.

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Georgia K. Stith

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